

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	5332	(charge near (trap or trapping))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/31 12:07
L2	103	(charge near (trap or trapping)) with trench	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/31 12:07
L3	37	(charge near (trap or trapping)) with trench with gate	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/31 12:14
L4	17077	(trench or via or opening) same charge same gate	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/31 12:15
L5	8527	(trench or via or opening) same charge same gate same (source or drain or source/drain or impurity or diffusion or doped or doping)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/31 12:16
L6	592	(trench or via or opening) same charge same gate same (source or drain or source/drain or impurity or diffusion or doped or doping) same (sidewall or spacer or (side near wall))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/31 12:16
L7	473	(trench or via or opening) same charge same gate same (source or drain or source/drain or impurity or diffusion or doped or doping) same (sidewall or spacer or (side near wall)) same (dielectric or insulating or oxide or insulation)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/31 12:17
L8	284	(charge near5 (accumulation or trap or trapping or accumulate or accumulating or accumulated)) with trench	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/31 12:18
L9	320	(charge near5 (accumulation or trap or trapping or accumulate or accumulating or accumulated)) with trench	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/31 12:19

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L10	104	(charge near5 (accumulation or trap or trapping or accumulate or accumulating or accumulated)) with trench with gate	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/31 12:23
L11	53	(charge near5 (accumulation or trap or trapping or accumulate or accumulating or accumulated) near2 (layer or film)) with trench with gate	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/31 12:25
L12	27	((charge near5 (accumulation or trap or trapping or accumulate or accumulating or accumulated) near2 (layer or film)) same trench same gate) and (ldd or (lightly near doped))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/31 12:27